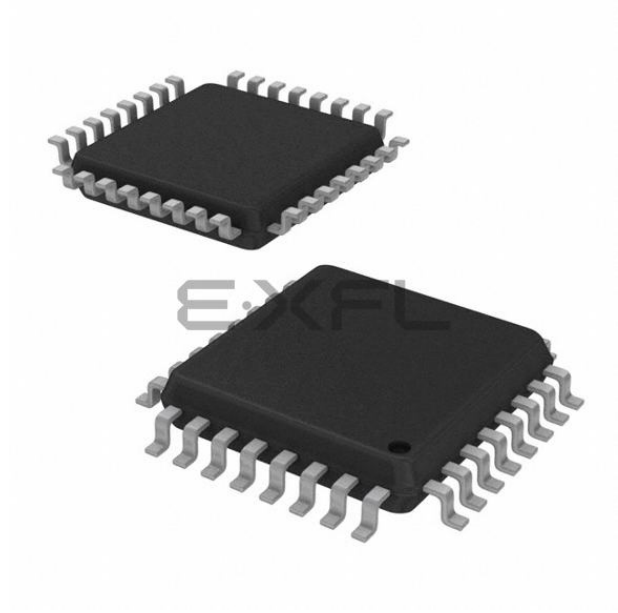

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Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	STM8
Core Size	8-Bit
Speed	16MHz
Connectivity	I²C, IrDA, LINbus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	28
Program Memory Size	8KB (8K x 8)
Program Memory Type	FLASH
EEPROM Size	128 x 8
RAM Size	1K x 8
Voltage - Supply (Vcc/Vdd)	2.95V ~ 5.5V
Data Converters	A/D 4x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-LQFP
Supplier Device Package	32-LQFP (7x7)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm8s003k3t6ctr

4.14.3 I²C

- I²C master features
  - Clock generation
  - Start and stop generation
- I²C slave features
  - Programmable I²C address detection
  - Stop bit detection
- Generation and detection of 7-bit/10-bit addressing and general call
- Supports different communication speeds
  - Standard speed (up to 100 kHz)
  - Fast speed (up to 400 kHz)

Table 6. STM8S003F3 pin description (continued)

Pin no.		Pin name	Type	Input			Output				Main function (after reset)	Default alternate function	Alternate function after remap [option bit]
TSSOP20	UFQFPN20			floating	wpu	Ext. interr.	High sink(1)	Speed	OD	PP			
14	11	PC4/ CLK_CCO/ TIM1_ CH4/AIN2/ [TIM1_ CH2N]	I/O	**X**	X	X	HS	O3	X	X	Port C4	Configurable clock output/Timer 1 - channel 4/Analog input 2	Timer 1 - inverted channel 2 [AFR7]
15	12	PC5/ SPI_SCK [TIM2_ CH1]	I/O	**X**	X	X	HS	O3	X	X	Port C5	SPI clock	Timer 2 - channel 1 [AFR0]
16	13	PC6/ SPI_MOSI [TIM1_ CH1]	I/O	**X**	X	X	HS	O3	X	X	Port C6	SPI master out/slave in	Timer 1 - channel 1 [AFR0]
17	14	PC7/ SPI_MISO [TIM1_ CH2]	I/O	**X**	X	X	HS	O3	X	X	Port C7	SPI master in/ slave out	Timer 1 - channel 2 [AFR0]
18	15	PD1/ SWIM(4)	I/O	X	**X**	X	HS	O4	X	X	Port D1	SWIM data interface	-
19	16	PD2/AIN3/ [TIM2_ CH3]	I/O	**X**	X	X	HS	O3	X	X	Port D2	Analog input 3	Timer 2 - channel 3 [AFR1]
20	17	PD3/ AIN4/ TIM2_ CH2/ ADC_ ETR	I/O	**X**	X	X	HS	O3	X	X	Port D3	Analog input 4/ Timer 2 - channel 2/ADC external trigger	-

1. I/O pins used simultaneously for high current source/sink must be uniformly spaced around the package. In addition, the total driven current must respect the absolute maximum ratings.
2. When the MCU is in halt/active-halt mode, PA1 is automatically configured in input weak pull-up and cannot be used for waking up the device. In this mode, the output state of PA1 is not driven. It is recommended d to use PA1 only in input mode if halt/active-halt is used in the application.
3. In the open-drain output column, "T" defines a true open-drain I/O (P-buffer, weak pull-up, and protection diode to VDD are not implemented).
4. The PD1 pin is in input pull-up during the reset phase and after internal reset release.

6 Memory and register map

6.1 Memory map

Figure 6. Memory map

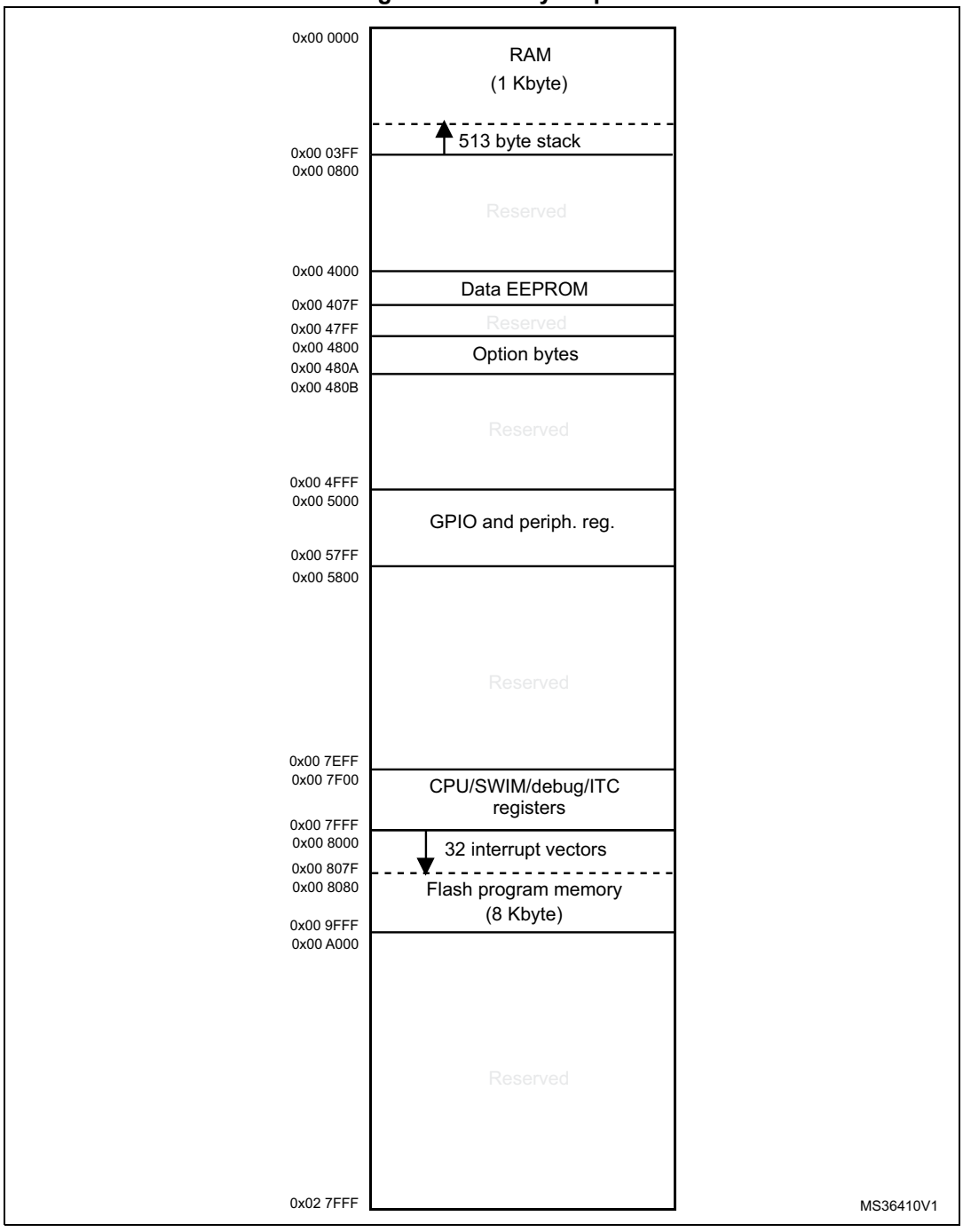


Table 7 lists the boundary addresses for each memory size. The top of the stack is at the RAM end address in each case.

Table 7. Flash, Data EEPROM and RAM boundary addresses

Memory area	Size (byte)	Start address	End address
Flash program memory	8 K	0x00 8000	0x00 9FFF
RAM	1 K	0x00 0000	0x00 03FF
Data EEPROM	128	0x00 4000	0x00 407F

6.2 Register map

6.2.1 I/O port hardware register map

Table 8. I/O port hardware register map

Address	Block	Register label	Register name	Reset status
0x00 5000	Port A	PA_ODR	Port A data output latch register	0x00
0x00 5001		PA_IDR	Port A input pin value register	0xXX(1)
0x00 5002		PA_DDR	Port A data direction register	0x00
0x00 5003		PA_CR1	Port A control register 1	0x00
0x00 5004		PA_CR2	Port A control register 2	0x00
0x00 5005	Port B	PB_ODR	Port B data output latch register	0x00
0x00 5006		PB_IDR	Port B input pin value register	0xXX(1)
0x00 5007		PB_DDR	Port B data direction register	0x00
0x00 5008		PB_CR1	Port B control register 1	0x00
0x00 5009		PB_CR2	Port B control register 2	0x00
0x00 500A	Port C	PC_ODR	Port C data output latch register	0x00
0x00 500B		PB_IDR	Port C input pin value register	0xXX(1)
0x00 500C		PC_DDR	Port C data direction register	0x00
0x00 500D		PC_CR1	Port C control register 1	0x00
0x00 500E		PC_CR2	Port C control register 2	0x00
0x00 500F	Port D	PD_ODR	Port D data output latch register	0x00
0x00 5010		PD_IDR	Port D input pin value register	0xXX(1)
0x00 5011		PD_DDR	Port D data direction register	0x00
0x00 5012		PD_CR1	Port D control register 1	0x02
0x00 5013		PD_CR2	Port D control register 2	0x00

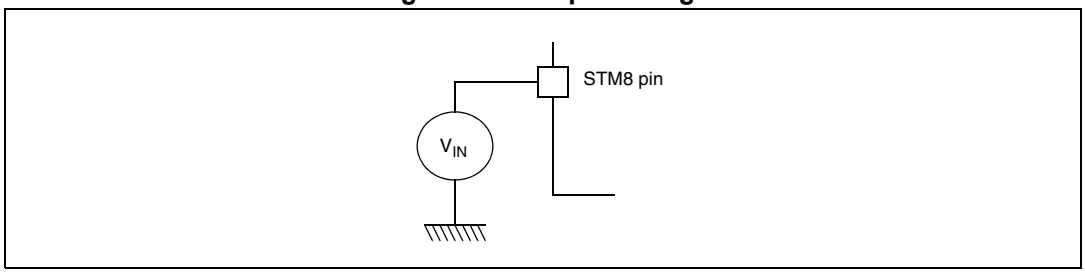
Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5250	TIM1	TIM1_CR1	TIM1 control register 1	0x00
0x00 5251		TIM1_CR2	TIM1 control register 2	0x00
0x00 5252		TIM1_SMCR	TIM1 slave mode control register	0x00
0x00 5253		TIM1_ETR	TIM1 external trigger register	0x00
0x00 5254		TIM1_IER	TIM1 Interrupt enable register	0x00
0x00 5255		TIM1_SR1	TIM1 status register 1	0x00
0x00 5256		TIM1_SR2	TIM1 status register 2	0x00
0x00 5257		TIM1_EGR	TIM1 event generation register	0x00
0x00 5258		TIM1_CCMR1	TIM1 capture/compare mode register 1	0x00
0x00 5259		TIM1_CCMR2	TIM1 capture/compare mode register 2	0x00
0x00 525A		TIM1_CCMR3	TIM1 capture/compare mode register 3	0x00
0x00 525B		TIM1_CCMR4	TIM1 capture/compare mode register 4	0x00
0x00 525C		TIM1_CCER1	TIM1 capture/compare enable register 1	0x00
0x00 525D		TIM1_CCER2	TIM1 capture/compare enable register 2	0x00
0x00 525E		TIM1_CNTRH	TIM1 counter high	0x00
0x00 525F		TIM1_CNTRL	TIM1 counter low	0x00
0x00 5260		TIM1_PSCRH	TIM1 prescaler register high	0x00
0x00 5261		TIM1_PSCRL	TIM1 prescaler register low	0x00
0x00 5262		TIM1_ARRH	TIM1 auto-reload register high	0xFF
0x00 5263		TIM1_ARRL	TIM1 auto-reload register low	0xFF
0x00 5264		TIM1_RCR	TIM1 repetition counter register	0x00
0x00 5265		TIM1_CCR1H	TIM1 capture/compare register 1 high	0x00
0x00 5266		TIM1_CCR1L	TIM1 capture/compare register 1 low	0x00
0x00 5267		TIM1_CCR2H	TIM1 capture/compare register 2 high	0x00
0x00 5268		TIM1_CCR2L	TIM1 capture/compare register 2 low	0x00
0x00 5269		TIM1_CCR3H	TIM1 capture/compare register 3 high	0x00
0x00 526A		TIM1_CCR3L	TIM1 capture/compare register 3 low	0x00
0x00 526B		TIM1_CCR4H	TIM1 capture/compare register 4 high	0x00
0x00 526C		TIM1_CCR4L	TIM1 capture/compare register 4 low	0x00
0x00 526D		TIM1_BKR	TIM1 break register	0x00
0x00 526E		TIM1_DTR	TIM1 dead-time register	0x00
0x00 526F		TIM1_OISR	TIM1 output idle state register	0x00
0x00 5270 to 0x00 52FF	Reserved area (147 byte)			

Table 9. General hardware register map (continued)

Address	Block	Register label	Register name	Reset status
0x00 5300	TIM2	TIM2_CR1	TIM2 control register 1	0x00
0x00 5301		Reserved		
0x00 5302		Reserved		
0x00 5303		TIM2_IER	TIM2 interrupt enable register	0x00
0x00 5304		TIM2_SR1	TIM2 status register 1	0x00
0x00 5305		TIM2_SR2	TIM2 status register 2	0x00
0x00 5306		TIM2_EGR	TIM2 event generation register	0x00
0x00 5307		TIM2_CCMR1	TIM2 capture/compare mode register 1	0x00
0x00 5308		TIM2_CCMR2	TIM2 capture/compare mode register 2	0x00
0x00 5309		TIM2_CCMR3	TIM2 capture/compare mode register 3	0x00
0x00 530A		TIM2_CCER1	TIM2 capture/compare enable register 1	0x00
0x00 530B		TIM2_CCER2	TIM2 capture/compare enable register 2	0x00
0x00 530C		TIM2_CNTRH	TIM2 counter high	0x00
0x00 530D		TIM2_CNTRL	TIM2 counter low	0x00
0x00 530E		TIM2_PSCR	TIM2 prescaler register	0x00
0x00 530F		TIM2_ARRH	TIM2 auto-reload register high	0xFF
0x00 5310		TIM2_ARRL	TIM2 auto-reload register low	0xFF
0x00 5311		TIM2_CCR1H	TIM2 capture/compare register 1 high	0x00
0x00 5312		TIM2_CCR1L	TIM2 capture/compare register 1 low	0x00
0x00 5313		TIM2_CCR2H	TIM2 capture/compare reg. 2 high	0x00
0x00 5314		TIM2_CCR2L	TIM2 capture/compare register 2 low	0x00
0x00 5315		TIM2_CCR3H	TIM2 capture/compare register 3 high	0x00
0x00 5316		TIM2_CCR3L	TIM2 capture/compare register 3 low	0x00
0x00 5317 to 0x00 533F	Reserved area (43 byte)			
0x00 5340	TIM4	TIM4_CR1	TIM4 control register 1	0x00
0x00 5341		Reserved		
0x00 5342		Reserved		
0x00 5343		TIM4_IER	TIM4 interrupt enable register	0x00
0x00 5344		TIM4_SR	TIM4 status register	0x00
0x00 5345		TIM4_EGR	TIM4 event generation register	0x00
0x00 5346		TIM4_CNTR	TIM4 counter	0x00
0x00 5347		TIM4_PSCR	TIM4 prescaler register	0x00
0x00 5348		TIM4_ARR	TIM4 auto-reload register	0xFF

Figure 8. Pin input voltage



9.2 Absolute maximum ratings

Stresses above those listed as 'absolute maximum ratings' may cause permanent damage to the device. This is a stress rating only and functional operation of the device under these conditions is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability.

Table 16. Voltage characteristics

Symbol	Ratings	Min	Max	Unit
V_{DDx} - V_{SS}	Supply voltage(1)	-0.3	6.5	V
V_{IN}	Input voltage on true open drain pins(2)	V_{SS} - 0.3	6.5	
	Input voltage on any other pin(2)	V_{SS} - 0.3	V_{DD} + 0.3	
$\lvert V_{DDx} - V_{DD} \rvert$	Variations between different power pins	-	50	mV
$\lvert V_{SSx} - V_{SS} \rvert$	Variations between all the different ground pins	-	50	
V_{ESD}	Electrostatic discharge voltage	see *Absolute maximum ratings (electrical sensitivity) on page 86*		-

1. All power (V_{DD}) and ground (V_{SS}) pins must always be connected to the external power supply
2. $I_{INJ(PIN)}$ must never be exceeded. This is implicitly insured if V_{IN} maximum is respected. If V_{IN} maximum cannot be respected, the injection current must be limited externally to the $I_{INJ(PIN)}$ value. A positive injection is induced by $V_{IN}>V_{DD}$ while a negative injection is induced by $V_{IN}<V_{SS}$. For true open-drain pads, there is no positive injection current, and the corresponding V_{IN} maximum must always be respected

9.3 Operating conditions

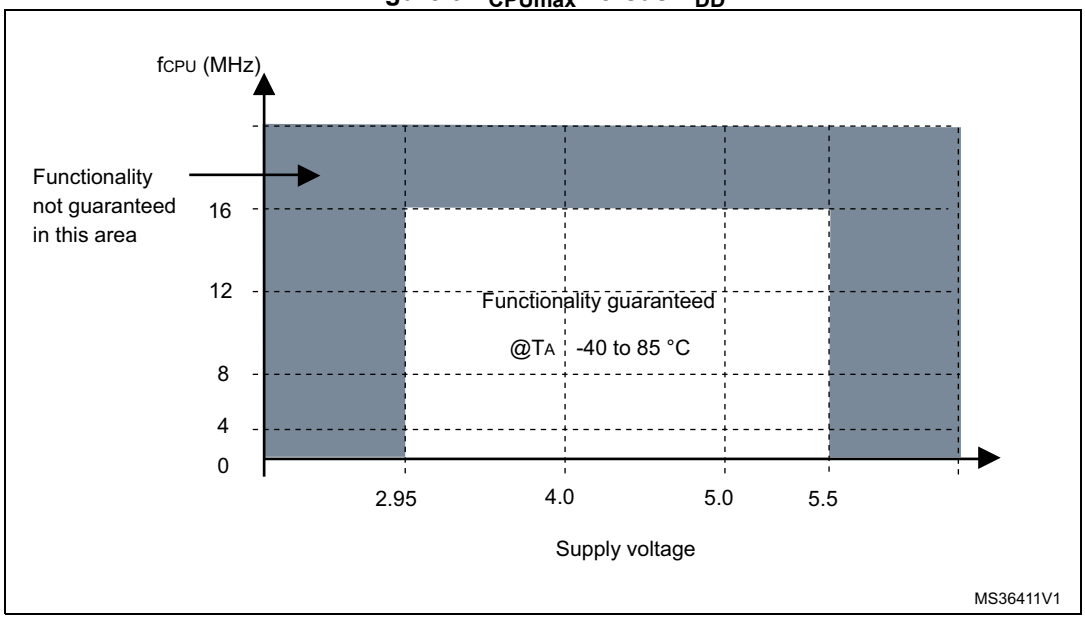
The device must be used in operating conditions that respect the parameters in *Table 19*. In addition, full account must be taken of all physical capacitor characteristics and tolerances.

Table 19. General operating conditions

Symbol	Parameter	Conditions	Min	Max	Unit
f_{CPU}	Internal CPU clock frequency	-	0	16	MHz
V_{DD}	Standard operating voltage	-	2.95	5.5	V
V_{CAP}(1)	C_{EXT}: capacitance of external capacitor	-	470	3300	nF
	ESR of external capacitor	At 1 MHz(2)	-	0.3	ohm
	ESL of external capacitor		-	15	nH
P_D(3)	Power dissipation at T_A = 85° C for suffix 6	TSSOP20	-	238	mW
		UFQFPN20	-	220	
		LQFP32	-	330	
T_A	Ambient temperature for 6 suffix version	Maximum power dissipation	-40	85	°C
T_J	Junction temperature range for 6 suffix version	-	-40	105	

1. Care should be taken when selecting the capacitor, due to its tolerance, as well as the parameter dependency on temperature, DC bias and frequency in addition to other factors. The parameter maximum values must be respected for the full application range.
2. This frequency of 1 MHz as a condition for V_{CAP} parameters is given by the design of the internal regulator.
3. To calculate $P_{Dmax}(T_A)$, use the formula $P_{Dmax} = (T_{Jmax} - T_A)/\Theta_{JA}$ (see *Section 10.4: Thermal characteristics on page 97*) with the value for T_{Jmax} given in *Table 19* above and the value for Θ_{JA} given in *Table 55: Thermal characteristics*.

Figure 9. f_{CPUmax} versus V_{DD}



Total current consumption in wait mode

Table 23. Total current consumption in wait mode at V_{DD} = 5 V

Symbol	Parameter	Conditions		Typ	Max(1)	Unit
$I_{DD(WFI)}$	Supply current in wait mode	$f_{CPU} = f_{MASTER}$ = 16 MHz	HSE crystal osc. (16 MHz)	1.6	-	mA
			HSE user ext. clock (16 MHz)	1.1	1.3	
			HSI RC osc. (16 MHz)	0.89	1.1	
		$f_{CPU} = f_{MASTER}/128$ = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.88	
		$f_{CPU} = f_{MASTER}/128$ = 15.625 kHz	HSI RC osc. (16 MHz/8)(2)	0.45	0.57	
		$f_{CPU} = f_{MASTER}$ = 128 kHz	LSI RC osc. (128 kHz)	0.4	0.54	

1. Data based on characterization results, not tested in production.
2. Default clock configuration measured with all peripherals off.

Table 24. Total current consumption in wait mode at V_{DD} = 3.3 V

Symbol	Parameter	Conditions		Typ	Max(1)	Unit
$I_{DD(WFI)}$	Supply current in wait mode	$f_{CPU} = f_{MASTER}$ = 16 MHz	HSE crystal osc. (16 MHz)	1.1	-	mA
			HSE user ext. clock (16 MHz)	1.1	1.3	
			HSI RC osc. (16 MHz)	0.89	1.1	
		$f_{CPU} = f_{MASTER}/128$ = 125 kHz	HSI RC osc. (16 MHz)	0.7	0.88	
		$f_{CPU} = f_{MASTER}/128$ = 15.625 kHz	HSI RC osc. (16 MHz/8)(2)	0.45	0.57	
		$f_{CPU} = f_{MASTER}/128$ = 15.625 kHz	LSI RC osc. (128 kHz)	0.4	0.54	

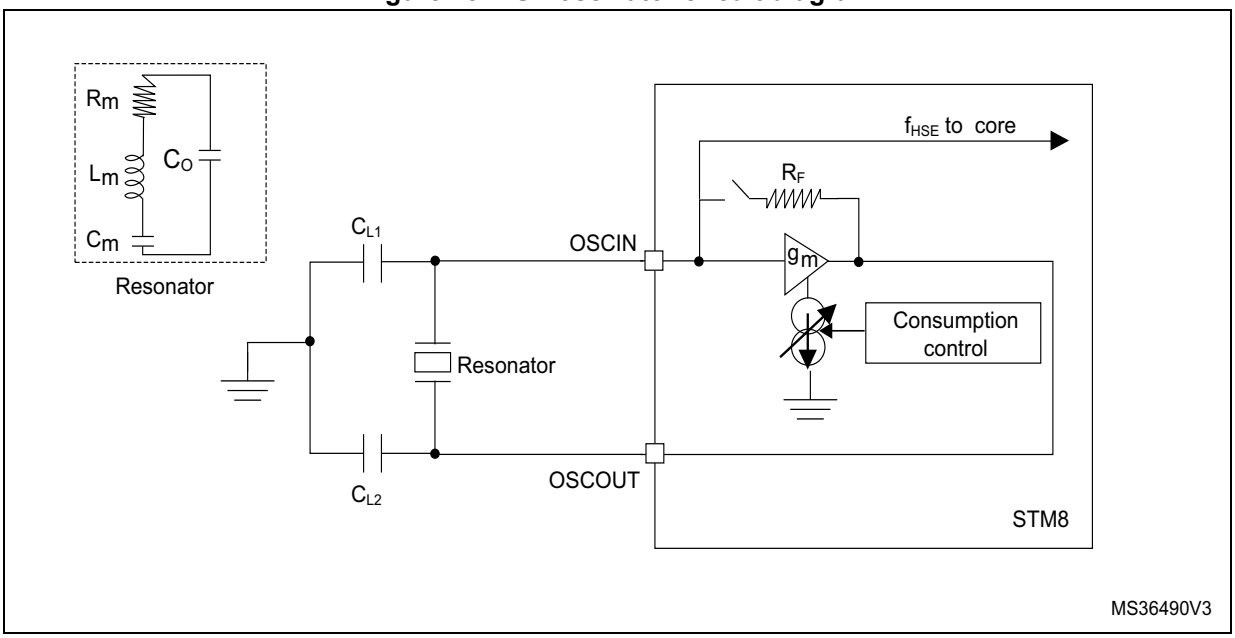
1. Data based on characterization results, not tested in production.
2. Default clock configuration measured with all peripherals off.

Table 33. HSE oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSE}	External high speed oscillator frequency	-	1	-	16	MHz
R_F	Feedback resistor	-	-	220	-	kΩ
$C^{(1)}$	Recommended load capacitance (2)	-	-	-	20	pF
$I_{DD(HSE)}$	HSE oscillator power consumption	C = 20 pF, f_{OSC} = 16 MHz	-	-	6 (startup) 1.6 (stabilized)(3)	mA
		C = 10 pF, f_{OSC} = 16 MHz	-	-	6 (startup) 1.2 (stabilized)(3)	
g_m	Oscillator transconductance	-	5	-	-	mA/V
$t_{SU(HSE)}^{(4)}$	Startup time	V_{DD} is stabilized	-	1	-	ms

1. C is approximately equivalent to 2 x crystal Cload.
2. The oscillator selection can be optimized in terms of supply current using a high quality resonator with small R_m value. Refer to crystal manufacturer for more details
3. Data based on characterization results, not tested in production.
4. $t_{SU(HSE)}$ is the start-up time measured from the moment it is enabled (by software) to a stabilized 16 MHz oscillation is reached. This value is measured for a standard crystal resonator and it can vary significantly with the crystal manufacturer.

Figure 18. HSE oscillator circuit diagram



HSE oscillator critical g_m formula

$g_{mcrit} = (2 \times \Pi \times f_{HSE})^2 \times R_m(2Co + C)^2$

R_m: Notional resistance (see crystal specification)
L_m: Notional inductance (see crystal specification)
C_m: Notional capacitance (see crystal specification)
Co: Shunt capacitance (see crystal specification)
C_{L1}=C_{L2}=C: Grounded external capacitance
$g_m >> g_{mcrit}$

9.3.4 Internal clock sources and timing characteristics

Subject to general operating conditions for V_{DD} and T_A.

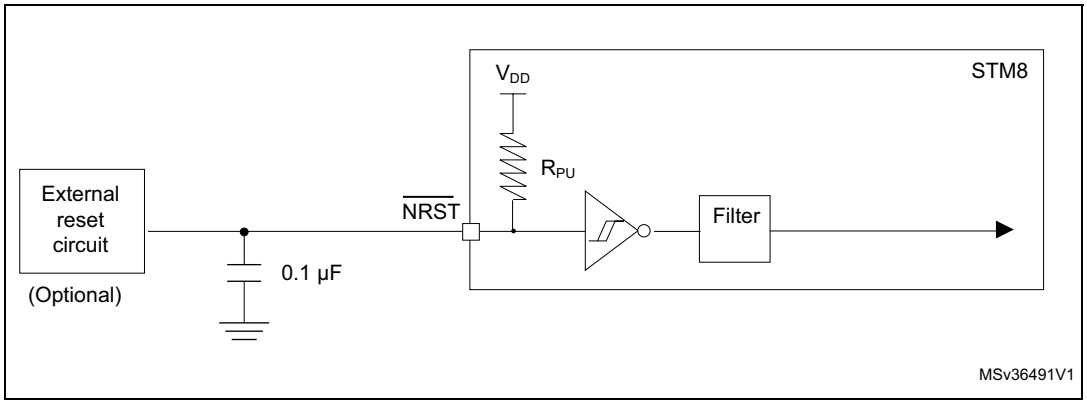
High speed internal RC oscillator (HSI)

Table 34. HSI oscillator characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{HSI}	Frequency	-	-	16	-	MHz
ACC_{HSI}	Accuracy of HSI oscillator	User-trimmed with the CLK_HSITRIMR register for given V_{DD} and T_A conditions(1)	-	-	1.0(2)	%
	Accuracy of HSI oscillator (factory calibrated)	V_{DD} = 5 V, T_A = 25 °C	-	5	-	
		V_{DD} = 5 V, -40 °C ≤ T_A ≤ 85 °C	-5	-	5	
$t_{su(HSI)}$	HSI oscillator wakeup time including calibration	-	-	-	1.0(2)	µs
$I_{DD(HSI)}$	HSI oscillator power consumption	-	-	170	250(3)	µA

1. See the application note.
2. Guaranteed by design, not tested in production.
3. Data based on characterization results, not tested in production

Figure 37. Recommended reset pin protection



9.3.8 SPI serial peripheral interface

Unless otherwise specified, the parameters given in *Table 43* are derived from tests performed under ambient temperature, f_{MASTER} frequency and V_{DD} supply voltage conditions. $t_{MASTER} = 1/f_{MASTER}$.

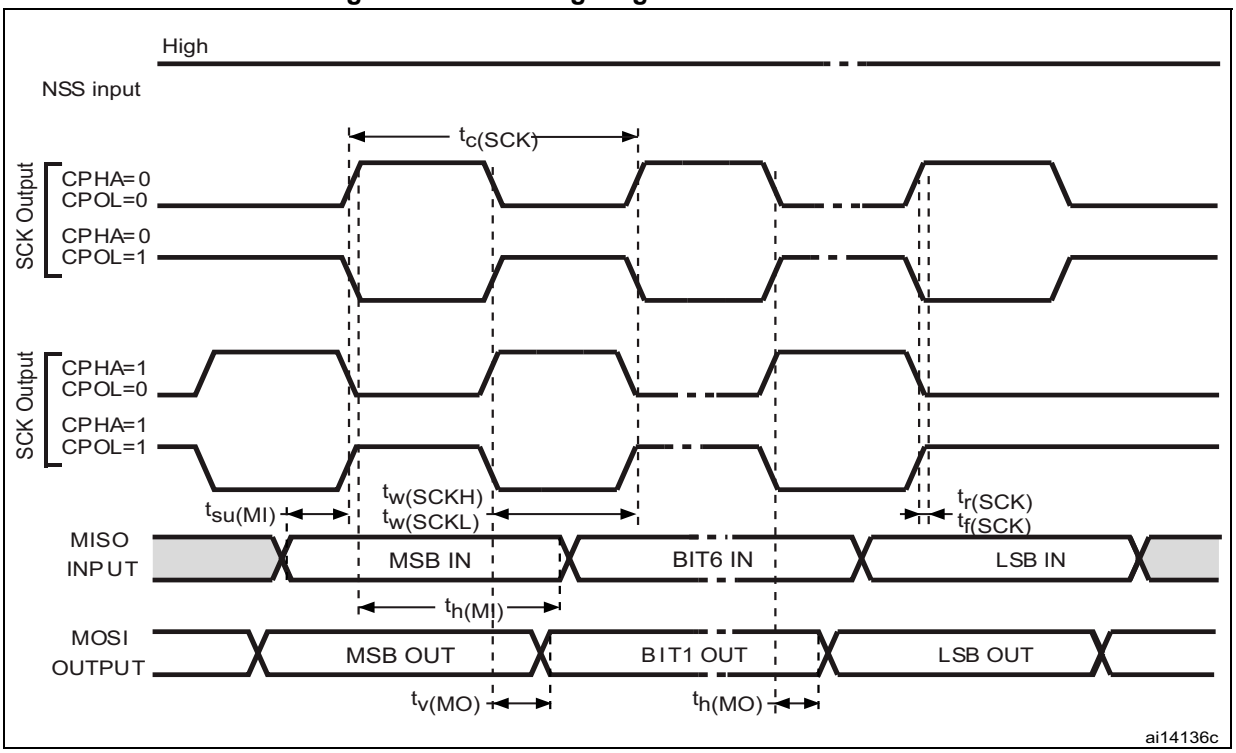
Refer to I/O port characteristics for more details on the input/output alternate function characteristics (NSS, SCK, MOSI, MISO).

Table 43. SPI characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
f_{SCK} $1/t_{c(SCK)}$	SPI clock frequency	Master mode	0	8	MHz
		Slave mode	0	7	
$t_{r(SCK)}$ $t_{f(SCK)}$	SPI clock rise and fall time	Capacitive load: C = 30 pF	-	25	ns
$t_{su(NSS)}$ (1)	NSS setup time	Slave mode	4 x t_{MASTER}	-	
$t_{h(NSS)}$ (1)	NSS hold time	Slave mode	70	-	
$t_{w(SCKH)}$ (1) $t_{w(SCKL)}$ (1)	SCK high and low time	Master mode	$t_{SCK}/2$ - 15	$t_{SCK}/2$ + 15	
$t_{su(MI)}$ (1) $t_{su(SI)}$ (1)	Data input setup time	Master mode	5	-	
		Slave mode	5	-	
$t_{h(MI)}$ (1) $t_{h(SI)}$ (1)	Data input hold time	Master mode	7	-	
		Slave mode	10	-	
$t_{a(SO)}$ (1)(2)	Data output access time	Slave mode	-	3 x t_{MASTER}	
$t_{dis(SO)}$ (1)(3)	Data output disable time	Slave mode	25	-	
$t_{v(SO)}$ (1)	Data output valid time	Slave mode (after enable edge)	-	65	
$t_{v(MO)}$ (1)	Data output valid time	Master mode (after enable edge)	-	30	
$t_{h(SO)}$ (1)	Data output hold time	Slave mode (after enable edge)	27	-	
$t_{h(MO)}$ (1)		Master mode (after enable edge)	11	-	

1. Values based on design simulation and/or characterization results, and not tested in production.
2. Min time is for the minimum time to drive the output and the max time is for the maximum time to validate the data.

Figure 40. SPI timing diagram - master mode(1)



1. Measurement points are done at CMOS levels: 0.3 V_{DD} and 0.7 V_{DD}.

9.3.10 10-bit ADC characteristics

Subject to general operating conditions for V_{DDA}, f_{MASTER}, and T_A unless otherwise specified.

Table 45. ADC characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
f_{ADC}	ADC clock frequency	V_{DDA} = 3 to 5.5 V	1	-	4	MHz
		V_{DDA} = 4.5 to 5.5 V	1	-	6	
V_{AIN}	Conversion voltage range(1)	-	V_{SS}	-	V_{DD}	V
C_{ADC}	Internal sample and hold capacitor	-	-	3	-	pF
t_S(1)	Sampling time	f_{ADC} = 4 MHz	-	0.75	-	µs
		f_{ADC} = 6 MHz	-	0.5	-	
t_{STAB}	Wakeup time from standby	-	-	7	-	µs
t_{CONV}	Total conversion time (including sampling time, 10-bit resolution)	f_{ADC} = 4 MHz	3.5			µs
		f_{ADC} = 6 MHz	2.33			µs
		-	14			$1/f_{ADC}$

1. During the sample time the input capacitance C_{AIN} (3 pF max) can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_S. After the end of the sample time t_S, changes of the analog input voltage have no effect on the conversion result. Values for the sample clock t_S depend on programming.

Table 46. ADC accuracy with R_{AIN} < 10 kΩ , V_{DD} = 5 V

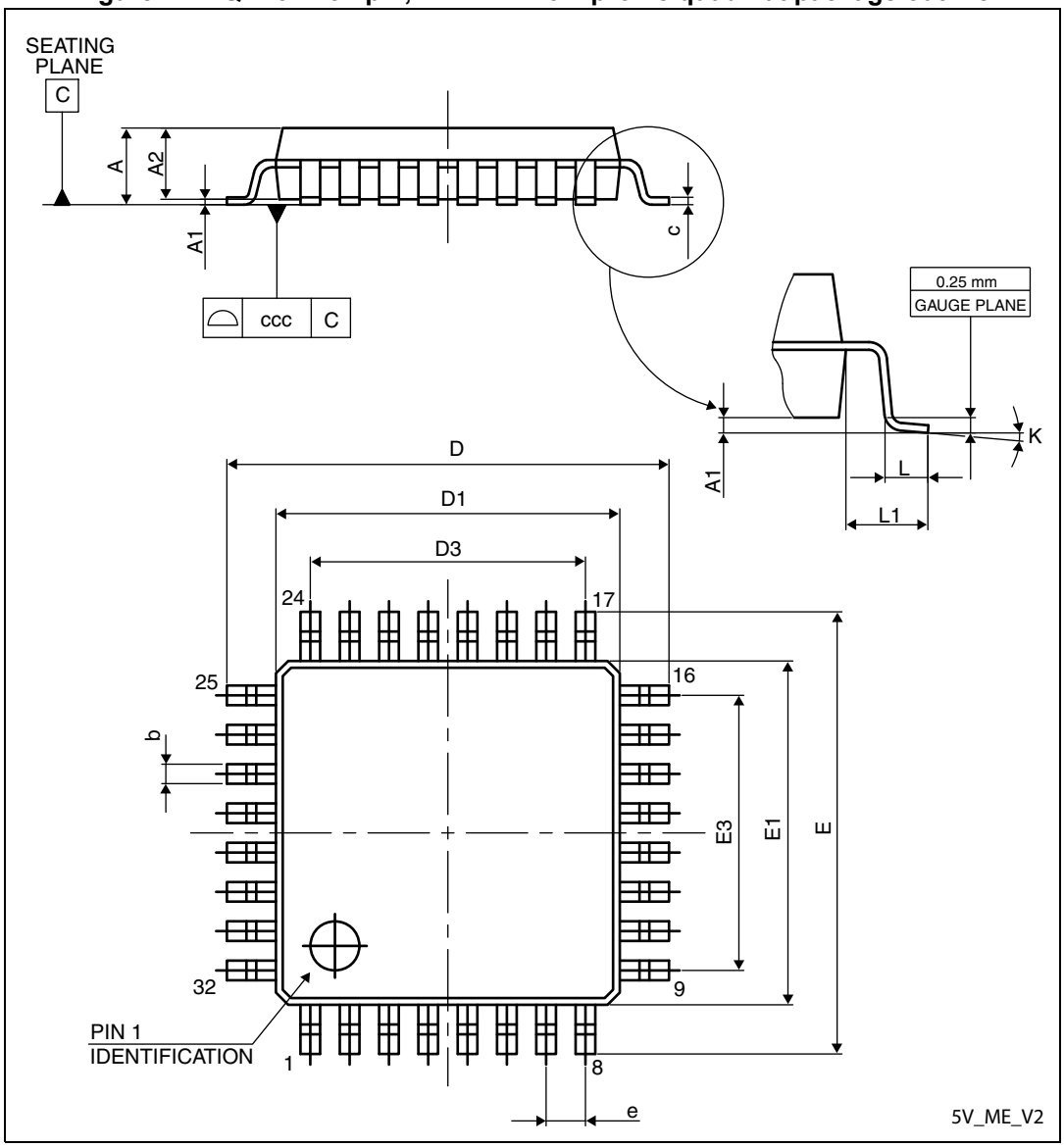
Symbol	Parameter	Conditions	Typ	Max(1)	Unit
$\|E_T\|$	Total unadjusted error (2)	f_{ADC} = 2 MHz	1.6	3.5	LSB
		f_{ADC} = 4 MHz	2.2	4	
		f_{ADC} = 6 MHz	2.4	4.5	
$\|E_O\|$	Offset error (2)	f_{ADC} = 2 MHz	1.1	2.5	
		f_{ADC} = 4 MHz	1.5	3	
		f_{ADC} = 6 MHz	1.8	3	
$\|E_G\|$	Gain error (2)	f_{ADC} = 2 MHz	1.5	3	
		f_{ADC} = 4 MHz	2.1	3	
		f_{ADC} = 6 MHz	2.2	4	
$\|E_D\|$	Differential linearity error (2)	f_{ADC} = 2 MHz	0.7	1.5	
		f_{ADC} = 4 MHz	0.7	1.5	
		f_{ADC} = 6 MHz	0.7	1.5	
$\|E_L\|$	Integral linearity error (2)	f_{ADC} = 2 MHz	0.6	1.5	
		f_{ADC} = 4 MHz	0.8	2	
		f_{ADC} = 6 MHz	0.8	2	

10 Package information

To meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at *www.st.com*. ECOPACK® is an ST trademark.

10.1 LQFP32 package information

Figure 44. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package outline



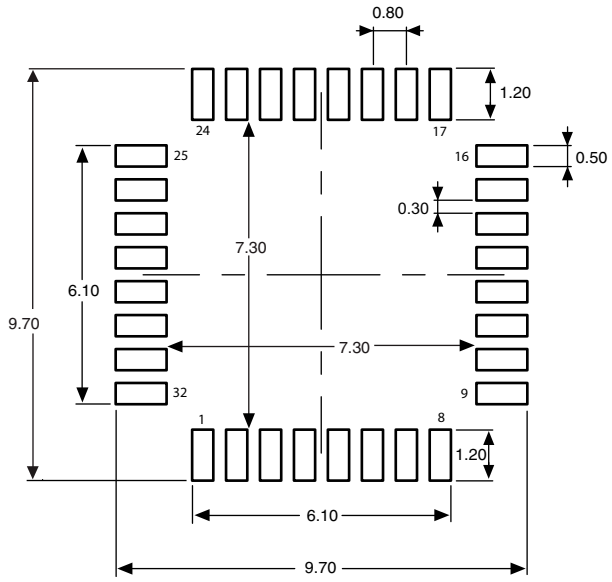
1. Drawing is not to scale.

Table 52. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches[1]		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.300	0.370	0.450	0.0118	0.0146	0.0177
c	0.090	-	0.200	0.0035	-	0.0079
D	8.800	9.000	9.200	0.3465	0.3543	0.3622
D1	6.800	7.000	7.200	0.2677	0.2756	0.2835
D3	-	5.600	-	-	0.2205	-
E	8.800	9.000	9.200	0.3465	0.3543	0.3622
E1	6.800	7.000	7.200	0.2677	0.2756	0.2835
E3	-	5.600	-	-	0.2205	-
e	-	0.800	-	-	0.0315	-
L	0.450	0.600	0.750	0.0177	0.0236	0.0295
L1	-	1.000	-	-	0.0394	-
k	0°	3.5°	7°	0°	3.5°	7°
ccc	-	-	0.100	-	-	0.0039

1. Values in inches are converted from mm and rounded to 4 decimal digits.

Figure 45. LQFP32 - 32-pin, 7 x 7 mm low-profile quad flat recommended footprint

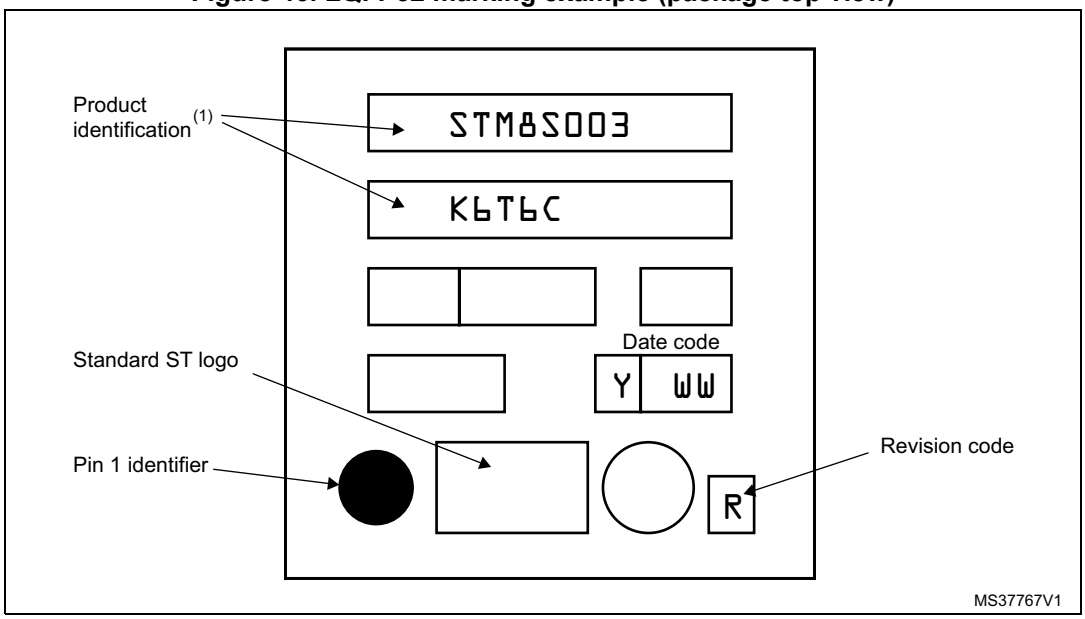


1. Dimensions are expressed in millimeters.

Device marking

The following figure gives an example of topside marking orientation versus pin 1 identifier location.

Figure 46. LQFP32 marking example (package top view)



1. Parts marked as "ES", "E" or accompanied by an Engineering Sample notification letter, are not yet qualified and therefore not yet ready to be used in production and any consequences deriving from such usage will not be at ST charge. In no event, ST will be liable for any customer usage of these engineering samples in production. ST Quality has to be contacted prior to any decision to use these Engineering Samples to run qualification activity.

10.4 Thermal characteristics

The maximum chip junction temperature (T_{Jmax}) must never exceed the values given in *Table 19: General operating conditions*.

The maximum chip-junction temperature, T_{Jmax}, in degrees Celsius, may be calculated using the following equation:

$T_{Jmax} = T_{Amax} + (P_{Dmax} \times \Theta_{JA})$

Where:

- T_{Amax} is the maximum ambient temperature in °C
- Θ_{JA} is the package junction-to-ambient thermal resistance in ° C/W
- P_{Dmax} is the sum of P_{INTmax} and $P_{I/Omax}$ ($P_{Dmax} = P_{INTmax} + P_{I/Omax}$)
- P_{INTmax} is the product of I_{DD} and V_{DD}, expressed in Watts. This is the maximum chip internal power.
- $P_{I/Omax}$ represents the maximum power dissipation on output pins, where: $P_{I/Omax} = \Sigma (V_{OL}*I_{OL}) + \Sigma((V_{DD}-V_{OH})*I_{OH})$, and taking account of the actual V_{OL}/I_{OL} and V_{OH}/I_{OH} of the I/Os at low and high level in the application.

Table 55. Thermal characteristics(1)

Symbol	Parameter	Value	Unit
Θ_{JA}	Thermal resistance junction-ambient LQFP 32 - 7 x 7 mm	60	°C/W
	Thermal resistance junction-ambient TSSOP20 - 4.4 mm	84	
	Thermal resistance junction-ambient UFQFPN20 -3 x 3 mm	90	

1. Thermal resistances are based on JEDEC JESD51-2 with 4-layer PCB in a natural convection environment.

10.4.1 Reference document

JESD51-2 integrated circuits thermal test method environment conditions - natural convection (still air). Available from www.jedec.org.